IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Akihiko OTOGURO, et al.

Serial Number: Not Yet Assigned

Filed: June 25, 2003

METHOD OF MANUFACTURING SEMICONDUCTOR DEVICE AND METHOD For: OF FORMING PATTERN

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

June 25, 2003

Sir:

In compliance with 37 CFR 1.56, Applicants call to the attention of the Patent and Trademark

Office the references listed on the attached PTO-1449.

A copy of each of the references are enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 01-2340,

Respectfully submitted, '

ARMSTRONG, WESTERMAN & HATTORI, LLP

James E. Armstrong I Attorney for Applicants

Reg. No. 42,266

JAM/jaz

Atty. Docket No. 030757

Suite 1000

1725 K Street, N.W.

Washington, D.C. 20006

(202) 659-2930

23850

PATENT TRADEMARK OFFICE

Enclosures: PTO-1449; References (4)

INFORMATION
DISCLOSURE
STATEMENT
PTO-1449

Atty. Docket No. 030757

Serial No. New Application

Applicant(s): Akihiko OTOGURO, et al.

Filing Date: June 25, 2003

Group Art Unit: Not Yet Assigned

U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date
				· · · · · · · · · · · · · · · · · · ·		· 	appropriate)
	AA		· · · · · · · · · · · · · · · · · · ·		•		
	AB						
	AC						
L-=	AD				· · · · · · · · · · · · · · · · · · ·		· · · · · · · · · · · · · · · · · · ·

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation (Yes or No)
	AE	4-5658	01/09/92	Japan	Yes-Abstract/Discussed in the specification
- · · · · · · · · · · · · · · · · · · ·	AF	60-254034	12/14/85	Japan	Yes-Abstract/Discussed in the specification
	AG	5-265224	10/15/93	Japan	Yes-Abstract/Discussed in the specification
	AH				
	ΑI			· · · · · · · · · · · · · · · · · · ·	

OTHER DOCUMENTS

	AJ AK	J.M. Moran et al.; "High resolution, steep profile resist patterns"; Journal of Vacuum Science Technology; Vol. 16; No. 6; November/December 1979; pp. 1620-1624./Discussed in the specification.
Examiner		Date Considered